Effect of Temperature and Banana quantity on Muffin Height

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Contents

1	Background	1
2	Materials2.1 Treatment structure2.2 Design structure2.3 Expected results2.4 Discussion of Designs	2 4
	Power analysis (optional) References	6

1 Background

Banana muffins, much like banana bread, present a unique baking challenge due to the inclusion of mashed bananas in the batter. While this ingredient contributes moisture and flavor, it can also result in a dense crumb if not balanced properly with other recipe components and baking conditions. In particular, oven temperature and banana quantity play a critical role in achieving a light, fluffy texture. This study begins with a standard banana muffin recipe and explores how adjusting the baking temperature affects the final crumb structure, with the goal of identifying optimal conditions for producing well-risen, tender muffins. The objective of this study is to find the best combination of oven temperature and banana quantity to prepare banana muffins. The main priority, however, is to find differences between muffin recipe.

2 Materials

2.1 Treatment structure

The proposed treatment structure is a 3×2 factorial treatment structure. The treatment factors will be oven temperature (250, 400, and 500 degrees Fahrenheit) and muffin recipe (control and extra banana). This treatment structure will allocate the same degrees of freedom for the treatment sources of variability, regardless of the design. Table 1 illustrates the degrees of freedom allocated to the sources of variability given by the treatment factors. Note that N depends on the design structure and is thus not defined here.

Table 1: Partial ANOVA table according to the 'What Would Fisher Do' technique - Treatment Sources of Variability. t indicates the number of temperature treatments, b indicates the number of banana recipe treatments, and N indicates the total number of observations.

Source	df
Temperature	t-1 = 3-1 = 2
Banana Recipe	b-1 = 2-1 = 1
Temp x Banana Recipe	(t-1)(b-1) = 2
Parallels	N-t
Total	N-1

2.2 Design structure

The facility that is available to bake the muffins includes one oven that will homogeneously bake one tray of muffins. There are three different proposed approaches: a randomized complete block design, a split-plot design with temperature in the whole plot, and a split-plot design with recipe in the whole plot. For demonstration, I will consider designs with 3 repetitions. See the section "Power Analysis" for an analysis of the number of repetitions.

2.2.1 Randomized complete block design

A block design consists of groups of experimental units that are approximately similar among them. In a randomized complete block design, each treatment appears the same number of times within a block. In this case, I envision running a randomized complete block design by baking muffins on three different days. I assume that day is the blocking factor and then, bake all treatments (i.e., all combinations of temperature and recipe) once each day (Figure 1).

Within a day, each treatment (i.e., C-250, C-400, C-500, B-250, B-400, B-500) is baked independently and one measurement is obtained from each treatment. The ANOVA table describing the treatment sources of variability is depicted in Table 2 and the final ANOVA table is depicted in Table 3. Both tables may also be rewritten as the statistical model

$$y = \mu + T_i + R_j + TR_{ij} + b_k + \varepsilon_{ijk},$$

$$b_j \sim N(0, \sigma_b^2),$$

$$\varepsilon_{ijk} \sim N(0, \sigma_\varepsilon^2),$$

where y_{ijk} is the observed height for the muffin from temperature i, recipe j, and day k, μ is the overall mean, T_i is the effect of the ith temperature, R_j is the effect of the jth recipe, $(TR)_{ij}$ is the interaction between the ith temperature and the jth recipe, b_k is the random effect from the kth day, and ε_{ijk} is the residual for the muffin from temperature i, recipe j, and day k.

Table 2: Design or Topographical Sources of Variability for an RCBD $\,$

Source df
Day (block)
$$r-1 = 3-1 = 2$$

Error(oven)
$$(tb-1)r = (6-1)*3 = 15$$

Source	df
Total	N-1 = 17

Table 3: Combined Table of the Sources of Variability

Source	df
Day	r-1 = 3-1 = 2
Temperature	t-1 = 3-1 = 2
Banana Recipe	b-1 = 2-1 = 1
Temp x Banana Recipe	(t-1)(b-1) = 2
Error(oven)	(tb-1)r - (t-1) - (b-2) - (t-1)(b-1) = 5*3 - 2 - 1 - 2 = 10
Total	N-1 = 17

2.2.2 Split-plot design with temperature in the whole plot

In this design, each oven temperature treatment (i.e., 250, 400, 500) is repeated 3 times within a day, and the recipe treatment is repeated 9 times (i.e., once for each oven). Within each oven, muffin batters for recipe C and B are prepared independently for each oven batch (Figure 2). One measurement is obtained from each temperature × recipe combination. The ANOVA table describing the treatment sources of variability is depicted in Table 2 and the final ANOVA table is depicted in Table 3.

The ANOVA table describing the treatment sources of variability is depicted in Table 4 and the final ANOVA table is depicted in Table 5. Both tables may also be rewritten as the statistical model

$$y = \mu + T_i + R_j + TR_{ij} + w_{i(k)} + \varepsilon_{ijk},$$

$$b_j \sim N(0, \sigma_b^2),$$

$$\varepsilon_{ijk} \sim N(0, \sigma_\varepsilon^2),$$

where y_{ijk} is the observed height for the muffin from temperature i, recipe j, and repetition k, μ is the overall mean, T_i is the effect of the ith temperature, R_j is the effect of the jth recipe, $(TR)_{ij}$ is the interaction between the ith temperature and the jth recipe, $w_{i(k)}$ is the whole plot random effect from the ith temperature and kth repetition, and ε_{ijk} is the residual for the muffin from temperature i, recipe j, and repetition k.

Table 4: Design or Topographical Sources of Variability for a splitplot design with temperature in the whole plot.

Source	df
Error(oven)	t*r-1 = 9-1 = 8
Error(oven x rep) Total	(b-1)t*r = 9 N-1 = 17

Table 5: Combined Table of the Sources of Variability

Source	df
Temperature	t-1 = 3-1 = 2

Source	df
Error(oven)	t*r-1 - (t-1) = -2 = 4
Banana Recipe	b-1 = 2-1 = 1
Temp x Banana Recipe	(t-1)(b-1) = 2
Error(oven x rep)	(b-1)tr - (b-1 + (t-1)(b-1)) = 9 - 3 = 6
Total	N-1 = 17

2.2.3 Split-plot design with recipe in the whole-plot

In this design, each oven temperature treatment (i.e., 250, 400, 500) is repeated 3 times within a day, and so is the recipe treatment. Three separate batters for recipe C and B are prepared independently and used to bake the muffins in a set of three oven temperatures (Figure 3). One measurement is obtained from each temperature \times recipe combination. The ANOVA table describing the treatment sources of variability is depicted in Table 2 and the final ANOVA table is depicted in Table 3.

The ANOVA table describing the treatment sources of variability is depicted in Table 6 and the final ANOVA table is depicted in Table 7. Both tables may also be rewritten as the statistical model

$$y = \mu + T_i + R_j + TR_{ij} + w_{j(k)} + \varepsilon_{ijk},$$

$$b_j \sim N(0, \sigma_b^2),$$

$$\varepsilon_{ijk} \sim N(0, \sigma_\varepsilon^2),$$

where y_{ijk} is the observed height for the muffin from temperature i, recipe j, and repetition k, μ is the overall mean, T_i is the effect of the ith temperature, R_j is the effect of the jth recipe, $(TR)_{ij}$ is the interaction between the ith temperature and the jth recipe, $w_{i(k)}$ is the whole plot random effect from the jth recipe and kth repetition, and ε_{ijk} is the residual for the muffin from temperature i, recipe j, and repetition k.

Table 6: Design or Topographical Sources of Variability for a splitplot design with batter in the whole plot.

Source	df
Error(batter)	b*r-1 = 6-1 = 5
Error(batter x rep) Total	(t-1)br = 26 = 12 N-1 = 17

Table 7: Combined Table of the Sources of Variability

Source	df
Temperature	b-1 = 2-1 = 1
Error(batter)	b*r-1 - (b-1) = 5 - 1 = 4
Banana Recipe	t-1 = 3-1 = 2
Temp x Banana Recipe	(b-1)(t-1) = 2
Error(batter x rep)	(t-1)b*r - (t-1 + (t-1)(b-1)) = 12 - 4 = 8
Total	N-1 = 17

2.3 Expected results

The effects of interest are T_i , R_j , and TR_{ij} .

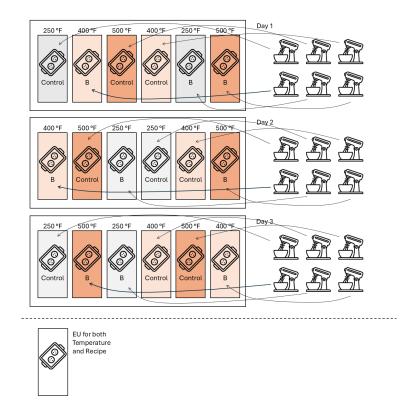


Figure 1: Figure 1. Schematic representation of the RCBD.

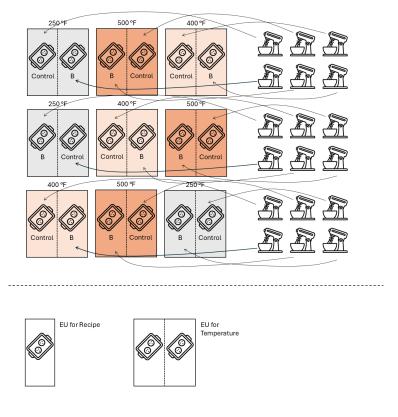


Figure 2: Figure 2. Schematic representation of the split-plot design with temperature in the whole plot

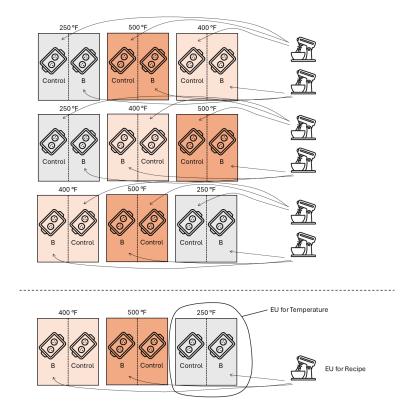


Figure 3: Figure 3. Schematic representation of the split-plot design with recipe in the whole plot

2.4 Discussion of Designs

Overall, the design that shows greater power for any treatment is the RCBD. However, this design is the most expensive (this design has the longest oven use hours), and most time-demanding (27 independent oven runs must be baked in this design). These downsides to this design do not seem to be compensated by only a slight improvement in power ().

Both the split-plot and the strip-plot designs can be considered appropriate designs because (i) they are not excessively demanding in terms of time/resources. Either one would be a good option. However, the split-plot design will slightly favour detecting differences between .

One potential downside of this design is that the number of repetitions was selected arbitrarily. See the section "Power analysis" for a more detailed description.

3 Power analysis (optional)

The previous example assumed 3 repetitions were enough. Based on our in-class experiment

4 References

When appropriate.